

Electronic Supplementary Information

Sulfur doped Co/SiO₂ catalysts for chirally selective synthesis of single walled carbon nanotubes

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1. Experimental methods

1.1 Catalyst preparation

Three Co/SiO₂ catalysts with 1 wt.% Co were prepared by the impregnation method using three Co precursors, including cobalt (II) acetylacetonate (Co(acac)₂, Sigma-Aldrich, 97%), Co (II) chloride (CoCl₂, Alfa Aesar, 97%), and Co (II) nitrate hexahydrate (Co(NO₃)₂·6H₂O, Sigma-Aldrich, 99.999%). Co(acac)₂ was dissolved in dichloromethane (Sigma-Aldrich, anhydrous, ≥99.8%), while Co(NO₃)₂·6H₂O and CoCl₂ was dissolved in deionized water. The Co precursor solutions were then added to fumed silicon dioxide powders (Cab-O-Sil, M-5, Sigma-Aldrich) with surface area of 254 m²/g. The mixtures were aged at room temperature for 1 h, and subsequently dried in an oven at 100 °C for 2h. The dried catalyst was further calcined under airflow of 20 sccm per gram of catalyst from room temperature to 400 °C at 1 °C/min, and then kept at 400°C for 1 h. These three catalysts were denoted as CoACAC/SiO₂, CoN/SiO₂, and CoCl/SiO₂. In order to dope S into Co/SiO₂ catalysts, the above calcined catalysts were impregnated by dilute sulphuric acid (H₂SO₄, 0.04 mol/L) at the 8 mL solution/g catalyst ratio for 1 h. Afterwards, the mixtures were dried and calcined again using the same procedure described above. The resulting S doped catalysts were denoted as CoACAC/SiO₂/S, CoN/SiO₂/S, and CoCl/SiO₂/S, respectively.

1.2 SWCNT growth

SWCNTs were synthesized in a CVD reactor under the same condition for all catalysts. A catalyst was first reduced under pure H₂ (1 bar, 50 sccm) from room temperature to 540 °C at 20 °C/min, and then further heated to 780 °C under an Ar flow (1 bar, 50 sccm). At 780 °C, pressured CO (6 bar, 200 sccm) replaced Ar and growth lasted for 1 h. The carbonyls in CO were removed by a Nanochem Purifilter from Matheson Gas Products.

1.3 SWCNT characterization

As-synthesized SWCNTs with catalysts were first dissolved in NaOH aqueous solution (1.5 mol/L) to remove SiO₂, and then filtered on a nylon membrane with 0.2 μm pores. Carbon deposits on filter membranes were further dispersed in 2 wt. % sodium dodecyl benzene sulphonate (SDBS, Aldrich) D₂O solution by sonication using a cup-horn ultrasonicator (SONICS, VCX-130) at 20 W for 1 h. SWCNT suspension obtained after centrifugation at 50,000 g for 1 h was characterised by photoluminescence (PL) and UV-vis-near-infrared (UV-vis-NIR) absorption spectroscopies. PL was conducted on a spectrofluorometer (Jobin-Yvon, Nanolog-3) with the excitation scanned from 450 to 950 nm and the emission collected from 900 to 1600 nm. The UV-vis-NIR absorption spectra were collected from 500 to 1600 nm on a spectrophotometer (Varian Cary 5000). As-synthesized SWCNTs with catalysts and SWCNTs filtered on nylon membranes after SiO₂ removal were both characterized by Raman spectroscopy. No significant differences were found on the two types of samples. Raman spectra were collected on a Ramanscope (Renishaw) in the backscattering configuration over several random spots on each sample under 514 and 785 nm laser excitations. The integration time of 10 s. Laser energy of 2.5–5 mW was used to prevent sample damages.

1.4 Catalyst characterization

The physicochemical properties of catalysts were evaluated by elemental analysis, H₂-temperature programmed reduction (H₂-TPR), and UV-vis diffuse reflectance spectroscopy. First, the weight fraction of S in the doped catalysts was determined by an elemental analyzer (Elementarvario, CHN). Around 5 mg of catalyst sample was used for each test. Each type of catalyst was tested three times to obtain the average value. Before each test, all samples were dried at 100 °C overnight. Next, the reducibility of Co species on undoped and S doped Co/SiO₂ catalysts was characterised by TPR. CoO (Sigma-Aldrich, 99.99%), Co₃O₄ (Sigma-Aldrich, 99.8%), CoSiO₃ (MP Biomedicals, ICN215905), CoCl₂ (Alfa Aesar, 97%), and CoSO₄·7H₂O (Sigma-Aldrich, 99%) were used as references for TPR analysis. Our TPR experimental setup was equipped with a thermal conductivity detector (TCD) of a gas chromatography (Techcomp 7900). An acetone-liquid N₂ trap was installed between a quartz cell and the TCD to condense

water or H₂S produced during catalyst reduction. In each test, 200 mg of catalysts or reference samples with equivalent Co loadings were loaded into a quartz cell. 5% H₂ in Ar was introduced to the quartz cell at 30 sccm, and pure Ar gas was used as a reference for the TCD. After the TCD baseline was stable, the temperature of the quartz cell was increased to 950 °C at 5 °C/min, and then held at 950 °C for 30 min. Last, UV–vis diffuse reflectance spectra of catalysts and Co reference samples were recorded on the spectrophotometer (Varian Cary 5000). The samples were first dried at 100 °C for 3 h, and then UV-vis spectra were recorded in the range of 200–800 nm with BaSO₄ as a reference.

2. Abundance of (*n,m*) species identified in PL

Table S1. Tabulated values of PL intensities and relative abundances of (*n,m*) species in SWCNTs produced on the CoACAC/SiO₂/S catalyst.

(<i>n,m</i>) index	Diameter d _t (nm)	Chiral angle θ (°)	E ₁₁ (nm)	E ₂₂ (nm)	PL intensity (counts)	Relative abundance, (%)
(6,5)	0.76	27.00	983	570	537.5	7.7
(7,3)	0.71	17.00	990	510	264.9	3.8
(7,5)	0.83	24.50	1023	642	155.0	2.2
(7,6)	0.90	27.46	1122	646	169.5	2.4
(8,4)	0.84	19.11	1111	578	241.0	3.4
(8,6)	0.97	25.28	1165	714	113.5	1.6
(8,7)	1.03	27.80	1264	726	403.8	5.8
(9,7)	1.10	25.87	1321	790	995.2	14.2
(9,8)	1.17	28.05	1414	822	2836.2	40.5
(10,6)	1.11	21.79	1380	754	535.4	7.7
(10,8)	1.24	26.30	1467	870	277.0	4.0
(10,9)	1.31	28.30	1562	886	469.5	6.7

Table S2. Tabulated values of PL intensities and relative abundances of (*n,m*) species in SWCNTs produced on the CoCl/SiO₂/S catalyst.

(<i>n,m</i>) index	Diameter d _t (nm)	Chiral angle θ (°)	E ₁₁ (nm)	E ₂₂ (nm)	PL intensity (counts)	Relative abundance, (%)
(6,5)	0.76	27.00	982	570	182.4	12.4
(7,3)	0.71	17.00	986	502	131.6	8.9
(7,5)	0.83	24.50	1023	642	96.1	6.5

(7,6)	0.90	27.46	1113	642	72.3	4.9
(8,4)	0.84	19.11	1109	578	75.4	5.1
(8,6)	0.97	25.28	1162	714	49.0	3.3
(8,7)	1.03	27.80	1265	722	59.5	4.0
(9,7)	1.10	25.87	1319	790	106.6	7.2
(9,8)	1.17	28.05	1412	818	478.2	32.7
(10,6)	1.11	21.79	1376	758	63.2	4.3
(10,8)	1.24	26.30	1469	866	36.4	2.5
(10,9)	1.31	28.30	1558	890	119.9	8.2

Table S3. Tabulated values of PL intensities and relative abundances of (n,m) species in SWCNTs produced on the CoN/SiO₂/S catalyst.

(n,m) index	Diameter d_t (nm)	Chiral angle θ (°)	E ₁₁ (nm)	E ₂₂ (nm)	PL intensity (counts)	Relative abundance, (%)
(6,5)	0.76	27.00	979	566	228.4	8.8
(7,3)	0.71	17.00	986	506	135.4	5.2
(7,5)	0.83	24.50	1024	642	121.8	4.7
(7,6)	0.90	27.46	1113	642	101.6	3.9
(8,4)	0.84	19.11	1110	578	120.8	4.7
(8,6)	0.97	25.28	1165	714	63.9	2.5
(8,7)	1.03	27.80	1263	726	120.6	4.7
(9,7)	1.10	25.87	1319	790	259.1	10.0
(9,8)	1.17	28.05	1413	818	1020.8	39.5
(10,6)	1.11	21.79	1377	750	143.7	5.6
(10,8)	1.24	26.30	1469	866	81.5	3.1
(10,9)	1.31	28.30	1558	886	189.4	7.3

3. Raman spectra of SWCNTs

Fig. S1 shows Raman spectra of carbon deposits grown from undoped and S doped Co/SiO₂ catalysts under 514 and 785 nm laser excitations. The radial breathing mode (RBM) peaks (below 400 cm⁻¹), D band and G band features can be used to evaluate the diameter and quality of resulting SWCNTs.¹ The intense RBM peaks and weak D band peaks from carbon deposits grown on CoCl/SiO₂ and CoACAC/SiO₂ suggest that high quality SWCNTs are produced. In contrast, the low intensity RBM peaks and intense D band peaks from carbon deposits grown on CoN/SiO₂ suggest that this catalyst is not active for SWCNT growth. The RBM peaks can be correlated with the (n,m) structures of

SWCNTs according to the Kataura plot computed by the tight-binding model.² We calculated the diameter of SWCNTs using the equation $\omega_{\text{RBM}}=223.5 \text{ cm}^{-1}/d_t+12.5 \text{ cm}^{-1}$, where ω_{RBM} and d_t are the RBM frequency and the diameter of SWCNTs.³ The RBM peaks in Fig. S1a and 1c at 238 and 267 cm^{-1} can be assigned to (8,6) and (7,6) according to the empirical Kataura plot,³ suggesting that the undoped catalysts mainly produce SWCNTs with diameters less than 1 nm. In comparison, all S doped Co/SiO₂ catalysts produce SWCNTs with high quality, as indicated by their intense RBM peaks and weak D band peaks (see Fig. S1b and S1d). The major RBM peaks centered around 202 and 213 cm^{-1} can be ascribed to the (9,8) and (9,7) with diameters around 1.1–1.17 nm.

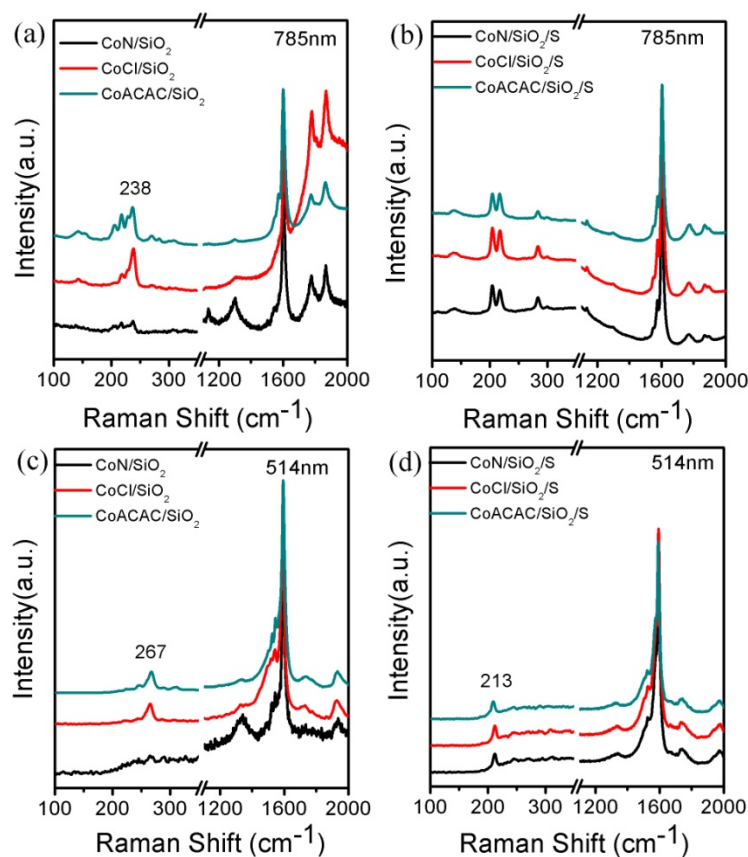


Fig. S1 Raman spectra of SWCNTs grown on undoped Co/SiO₂ catalysts (a and c) and S doped Co/SiO₂ (b and d) under 785 and 514 nm laser excitations, respectively. The regions on the left correspond to RBM peaks, while the regions on the right correspond to D and G bands.

4. UV-vis spectra of Co/SiO₂ catalysts

UV-vis diffuse reflectance spectroscopy was used to study the surface chemistry of undoped and S doped Co/SiO₂ catalysts. Fig. S2 shows that the spectrum of CoN/SiO₂ is similar to that of Co₃O₄, having two broad peaks at around 400 and 720 nm, respectively. These two peaks can be assigned to the ν_1 ⁴A_{1g} → ¹T_{1g} and ν_2 ¹A_{1g} → ¹T_{2g} transitions of octahedral configured Co³⁺ ions.⁴ The spectrum of CoCl/SiO₂ shows two broad peaks around 550 and 720 nm, which suggests the presence of CoO_x and CoCl₂. CoACAC/SiO₂ has two peaks around 570 and 650 nm, suggesting the formation of surface Co silicates.⁵ In contrast, the three S doped Co/SiO₂ catalysts all have a broad peak around 535 nm similar to that of CoSO₄, suggesting the existence of Co species bonded to SO₄²⁻. We also found that all of them have a similar light pink color.

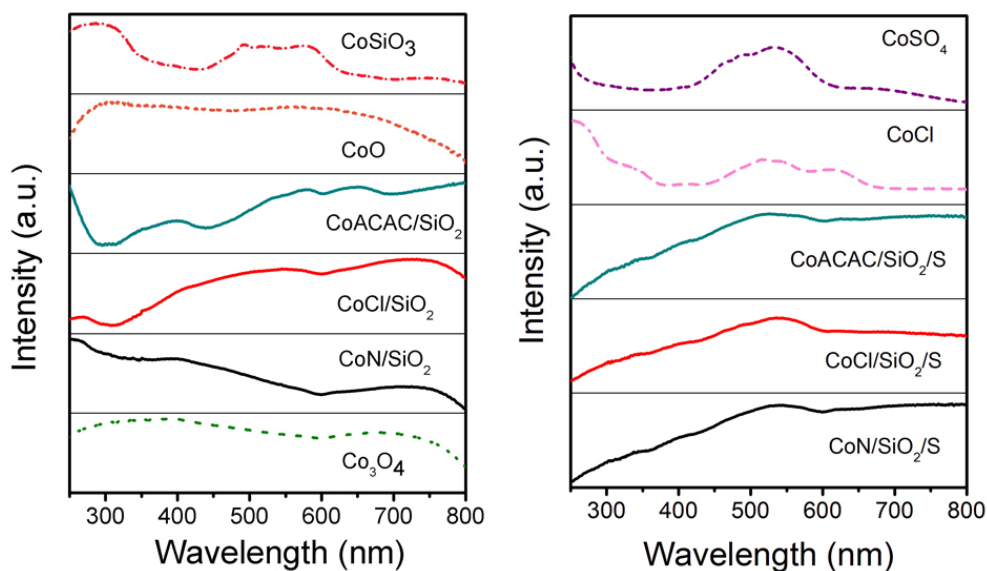


Fig. S2 UV-vis diffuse reflectance spectra: (a) Co/SiO₂ catalysts and references (Co₃O₄, CoO and CoSiO₃), (b) S doped Co/SiO₂ catalysts as well as the reference CoCl and CoSO₄.

5. Transmission Electron Microscopy (TEM) images

One milligram of as-synthesized SWCNTs together with the catalyst (CoACAC/SiO₂/S) was sonicated with 5 mL of anhydrous ethanol for 1 h, and a drop of the suspension was applied to a copper grid with holey carbon film. The grid was inserted into a Philips Tecnai 12 electron microscope, and TEM images were taken at an operation voltage of 120 kV. TEM images in Fig. S3 shows that SWCNTs grown from Co nanoparticles on SiO₂ form nanotube bundles. The diameter of individual tubes is about 1.2 nm, which agrees with spectroscopic results. Because active Co nanoparticles would

be embedded under or near SiO₂ surface, we are still unable to quantify their size and composition in TEM analysis.

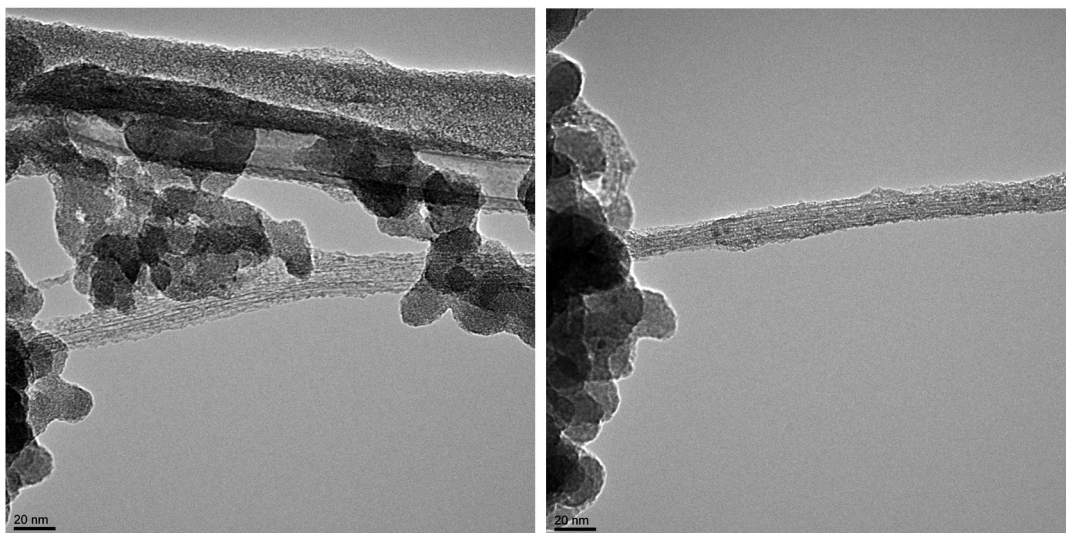


Fig. S3 TEM images of SWCNTs and catalyst particles.

6. (NH₄)₂SO₄ doped Co/SiO₂ catalyst

6.1 Doping method

The CoN/SiO₂ catalyst was impregnated by ammonium sulfate ((NH₄)₂SO₄, 0.2 mol/L) at the 8 mL solution/g catalyst ratio for 1 h, and subsequently dried in an oven at 100 °C for 2 h. The dried catalyst was further calcined under air flow of 20 sccm per gram of catalyst from room temperature to 400 °C at 1 °C/min, and then kept at 400 °C for 1 h. The resulting S doped catalyst was denoted as CoN/SiO₂/AS.

6.2 PL and abundance of (n,m) species

The PL map in Fig. S4 shows that (NH₄)₂SO₄ doped CoN/SiO₂ catalyst produces dominantly (6,5) tubes (35.4 %) while (9,8) tubes are present in smaller amount (11.3 %). This can be attributed to the doping of S. Overall, CoN/SiO₂/AS is less selective to (9,8) SWCNTs as compared to CoN/SiO₂/S.

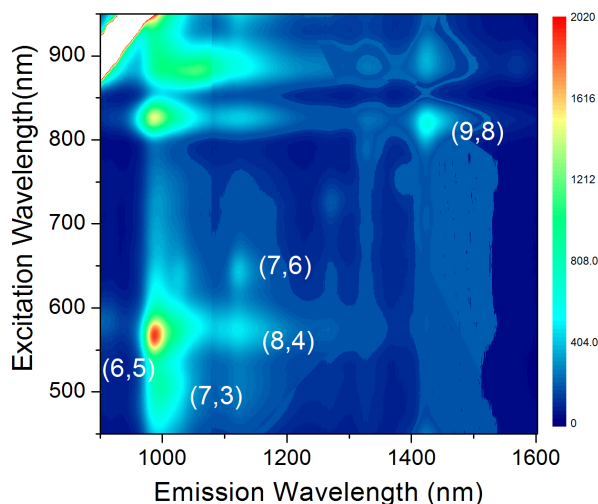


Fig. S4 PL map of SDBS-dispersed SWCNTs grown on the CoN/SiO₂/AS catalyst.

Table S4. Tabulated values of PL intensities and relative abundances of (n,m) species in SWCNTs produced on the CoN/SiO₂/AS catalyst.

(n,m) index	Diameter d_t (nm)	Chiral angle θ (°)	E ₁₁ (nm)	E ₂₂ (nm)	PL intensity (counts)	Relative abundance, (%)
(6,5)	0.76	27.00	991	566	1928.3	35.40%
(7,3)	0.71	17.00	989	502	734.1	13.50%
(7,5)	0.83	24.50	1025	638	408.4	7.50%
(7,6)	0.90	27.46	1127	642	409.7	7.50%
(8,4)	0.84	19.11	1120	574	486.4	8.90%
(8,6)	0.97	25.28	1163	718	138.3	2.50%
(8,7)	1.03	27.80	1269	726	173.7	3.20%
(9,7)	1.10	25.87	1330	790	216.7	4.00%
(9,8)	1.17	28.05	1428	822	613.6	11.30%
(10,6)	1.11	21.79	1377	754	123.1	2.30%
(10,8)	1.24	26.30	1470	866	105.7	1.90%
(10,9)	1.31	28.30	1557	890	107.2	2.00%

6.3 Absorption spectra

The strong absorption peaks at 1415 and 810 nm in Fig. S5 correspond to the E₁₁^S and E₂₂^S transition of (9,8). The peak around 983 nm from the E₁₁^S transition of (6,5) is much more intense compared to that of SWCNTs grown from CoN/SiO₂/S, indicating more (6,5) tubes are grown on CoN/SiO₂/AS. As the absorption coefficient of (9,8) is higher than that of (6,5), the absorption peaks from (9,8) look larger than that of (6,5). A few

absorption peaks below 700 nm can be assigned to either the E_{11}^M transition of metallic (9,6) and (10,10) or the E_{22}^S transition of semiconducting (6,5).

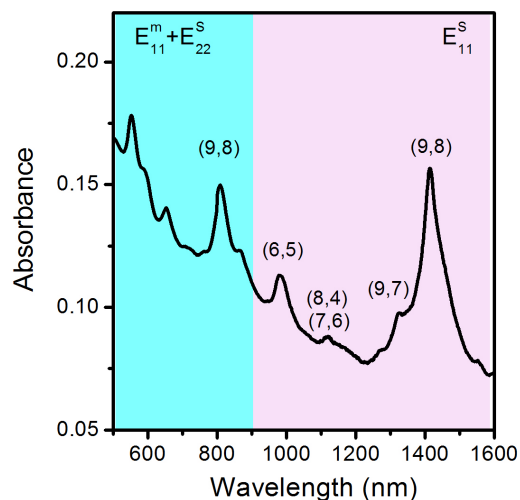


Fig. S5 UV-vis-NIR absorption spectra of SDBS-dispersed SWCNTs grown on CoN/SiO₂/AS.

6.4 H₂-TPR

The TPR profile of CoN/SiO₂/AS has an intense peak around 519 °C, which is similar to that of CoN/SiO₂/S shown in Fig. 2c. However, the large peak around 800 °C of CoN/SiO₂/S shown in Fig. 2c is very weak in Fig. S6. The CoN/SiO₂/AS has a broad peak from 425–800 °C, suggesting the existence of several Co species, including unreacted CoO_x, Co hydrosilicate, and surface Co silicate.⁶

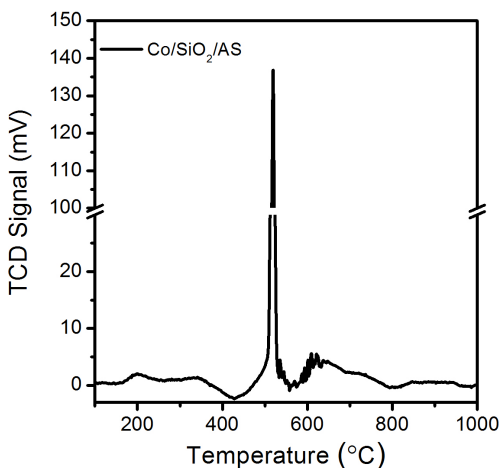


Fig. S6 H₂-TPR profile of the CoN/SiO₂/AS catalyst.

6.5 UV–vis diffuse reflectance spectroscopy

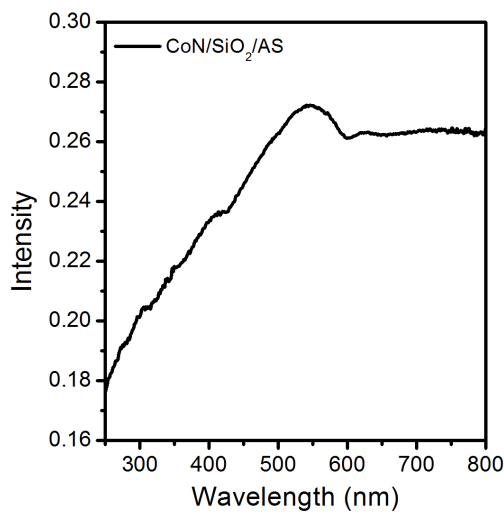


Fig. S7 UV–vis diffuse reflectance spectrum of CoN/SiO₂/AS.

Fig. S7 shows that the UV–vis spectrum of CoN/SiO₂/AS catalyst has a broad peak around 535 nm similar to that of CoN/SiO₂/S, suggesting the existence of Co species bonded to SO₄²⁻.

7. References

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